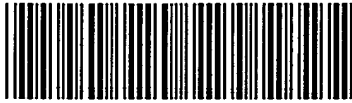


Search Notes

Application/Control No.

10/757,877

Examiner

Paul D. Kim

Applicant(s)/Patent under
Reexamination

FEIST ET AL.

Art Unit

3729

SEARCHED

Class	Subclass	Date	Examiner
29	592.1 602.1 603.13 604 856 858	8/15/2005	PK
428	64.2-64.4		
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427	127 162		
	240 369 370		
264	319 320 322		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Reviewed Parent Application 09/846,888 US PAT. 6,715,200	8/15/2005	PK
Text Search EAST/NPL (IEEE)	8/15/2005	PK
Updated Text Search EAST	4/19/2006	PK